

*Shu*



TSMC-01-1357D

May 11, 2004

To: Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572  
28 Davis Avenue  
Poughkeepsie, N.Y. 12603

Subject:

Serial No. 10/821,270 04/08/04

Yi-Hsu Wu et al.

WHOLE CHIP ESD PROTECTION

#### INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation  
In An Application.

The following Patents and/or Publications are submitted to  
comply with the duty of disclosure under CFR 1.97-1.99 and  
37 CFR 1.56.

#### CERTIFICATE OF MAILING

I hereby certify that this correspondence is being  
deposited with the United States Postal Service as first class  
mail in an envelope addressed to: Commissioner for Patents,  
P.O. Box 1450, Alexandria, VA 22313-1450, on May 17, 2004.

Stephen B. Ackerman, Reg. # 37761

Signature/Date

*Stephen B. Ackerman* 5/17/04

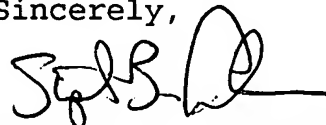
TSMC-01-1357D

U.S. Patent 6,344,412 to Ichikawa et al., "Integrated ESD Protection Method and System," describes a method and a system for protecting integrated circuits from electrostatic discharge damage.

U.S. Patent 6,262,873 to Pequignot et al., "Method for Providing ESD Protection for an Integrated Circuit," discloses a method for providing electrostatic protection for integrated circuits.

U.S. Patent 6,218,704 to Brown et al., "ESD Protection Structure and Method," discloses an integrated circuit structure and method for electrostatic discharge protection for chips.

Sincerely,

A handwritten signature in black ink, appearing to read 'SBA', with a large, stylized loop at the end.

Stephen B. Ackerman,  
Reg. No. 37761

## INFORMATION DISCLOSURE CITATION

MAY 19 2004 IN AN APPLICATION

(Use several sheets if necessary)

TSMC-01-13570

10/821,270

Applicant

Yi-Hsu Wu et al.

Filing Date

04/08/04

Group Art Unit

## U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILED DATE IF APPROPRIATE
	6344412	2/5/02	Ichikawa et al.	438	661	3/10/00
	6262873	7/17/01	Peguignot et al.	361	111	9/7/00
	6218704	4/17/01	Brown et al.	257	355	5/7/97

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Portion of Pages, Etc.)


EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.